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U.S. Department of Commerce Att rney Docket N . 0756-1936 Form PTO-1449 Serial N . N t Yet Assigned (Rev. 8-83) Patent and Trademark Office INFORMATION DISCLOSURE STATEMENT Applicant: Shunpei YAMAZAKI et al. (Use several sheets if necessary) Filing Date: February 23, 1999 Group: 2812 U.S. PATENT DOCUMENTS Class Subclass Filing Date Examiner **Document Number** Date Name Initial (if appropriate) 4,727,044 2/23/88 Yamazaki 9/25/90 Yamazaki 4,959,700 5,142,344 5/24/91 Yamazaki 11/15/83 Naem et al. 4.415.383 6/18/85 **Nishimura** 4,523,962 2/14/84 Teng 4,431,459 7/25/89 Troxel et al. 4,851,363 9/25/90 Yamazaki 2/3/88 4,959,700 4/26/94 Masumo et al. 5/10/91 437 40 5,306,651 437 101 10/24/83 4,561,906 12/31/85 Calder et al. 2/25/92 Yamazaki et al. 437 101 6/29/81 5.091.334 257 66 6/13/90 12/21/93 Yamazaki 5,272,361 FOREIGN PATENT DOCUMENTS Class Subclass **Translation Document Number** Date Country Yes No 7/14/84 59-121876 Japan Abst 12/4/85 Abst 60-245174 Japan 6-59280 3/4/94 Abst Japan 5-206468 8/13/93 Japan Abst 1-187983 7/27/89 Abst Japan OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) Sameshima et al., Japanese Journal of Applied Physics, "XeCI Excimer Laser Annealing Used to Fabricate Poly-Si TFT's", Vol. 28, No. 10, October, 1989, p. 1789-1793. Sera et al., "High Performance TFT's Fabricated by XeCI Excimer Laser Annealing of Hydrogenated Amorphous Silicon Film", IEEE Transactions, 36 (1989), p. 2868-2872. **Date Considered Examiner** \*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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U.S. Department of Commerce Patent and Trademark Office Att rn y D cket N . 0756-1936

Serial No. Not Yet Assigned

## INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

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